

PHOTOCOUPLED GaAlAs IRED & PHOTO-IC

TLP113

TENTATIVE DATA

ISOLATED LINE RECEIVER

SIMPLEX/MULTIPLEX DATA TRANSMISSION

COMPUTER-PERIPHERAL INTERFACE

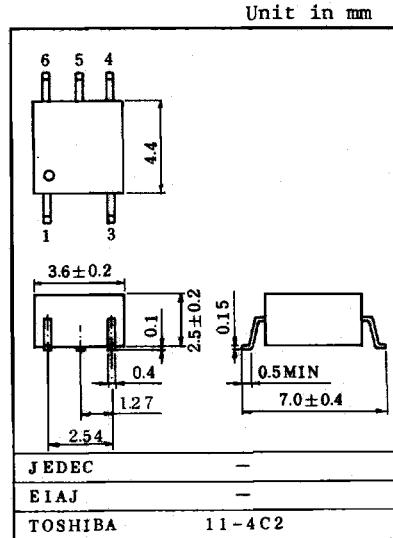
MICROPROCESSOR SYSTEM INTERFACE

DIGITAL ISOLATION FOR A/D, D/A CONVERSION

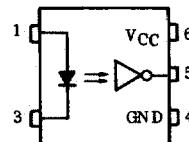
The TOSHIBA MINI FLAT COUPLER TLP113 is a small outline coupler, suitable for surface mount assembly.

TLP113 consists of a GaAlAs light emitting diode, optically coupled to an integrated high gain, high speed photodetector whose output is an open collector, schottky clamped transistor.

- . Input Current Thresholds : $I_F = 10\text{mA}(\text{Max.})$
- . Switching Speed : $10\text{MBd}(\text{Typ.})$
- . TTL/LSTTL Compatible : $V_{CC} = 5\text{V}$
- . Guaranteed Performance Over Temp. : $0\text{~}70^\circ\text{C}$
- . Isolation Voltage : $2500\text{V}_{\text{rms}}(\text{Min.})$



PIN CONFIGURATION (TOP VIEW)

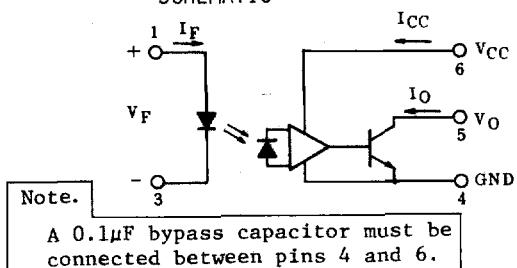


1. ANODE
3. CATHODE
4. GND
5. OUTPUT
(OPEN COLLECTOR)
6. VCC

TRUTH TABLE (Positive Logic)

INPUT	OUTPUT
H	L
L	H

SCHEMATIC



TLP113

MAXIMUM RATINGS (Ta=25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT
LED	Forward Current	I _F	20	mA
	Pulse Forward Current (Note 1)	I _{FP}	40	mA
	Peak Transient Forward Current (Note 2)	I _{FPPT}	1	A
	Reverse Voltage	V _R	5	V
DETECTOR	Output Current	I _O	25	mA
	Output Voltage	V _O	7	V
	Supply Voltage (1 Minute Maximum)	V _{CC}	7	V
	Output Power Dissipation	P _O	40	mW
Operating Temperature Range		T _{opr}	-40~85	°C
Storage Temperature Range		T _{stg}	-55~125	°C
Lead Solder Temperature (10 sec.)		T _{sold}	260	°C
Isolation Voltage (AC, 1 min., RH≤60%, Note 4)		BVS	2500	V _{rms}

Note 1 : 50% duty cycle, 1ms pulse width.

Note 2 : Pulse width≤1μs, 300pps.

RECOMMENDED OPERATING CONDITIONS

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT
Input Voltage, Low Level	V _{FL}	-3	0	1.0	V
Input Current, High Level	I _{FH}	13*	16	20	mA
Supply Voltage	V _{CC}	4.5	5	5.5	V
Fan Out (TTL Load, Each Channel)	N	-	-	8	
Operating Temperature	T _{opr}	0	-	70	°C

* 13mA is a guard banded value which allows for at least 20% CTR degradation.

Initial input current threshold value is 10mA or less.

ELECTRICAL CHARACTERISTICS

(Unless otherwise specified, $T_a=0\text{--}70^\circ\text{C}$, $V_{CC}=4.5\text{--}5.5\text{V}$, $V_{FL}\leq 1.0\text{V}$)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Forward Voltage	V_F	$I_F=10\text{mA}$, $T_a=25^\circ\text{C}$	-	1.65	1.80	V
Forward Voltage Temperature Coefficient	V_F/T_a	$I_F=10\text{mA}$	-	-2	-	$\text{mV}/^\circ\text{C}$
Reverse Current	I_R	$V_R=5\text{V}$, $T_a=25^\circ\text{C}$	-	-	10	μA
Capacitance Between Terminals	C_T	$V_F=0$, $f=1\text{MHz}$, $T_a=25^\circ\text{C}$	-	45	-	pF
High Level Output Current	I_{OH}	$V_F=1.0$, $V_O=5.5\text{V}$	-	-	250	μA
		$V_F=1.0$, $V_O=5.5\text{V}$, $T_a=25^\circ\text{C}$	-	0.5	10	
Low Level Output Voltage	V_{OL}	$I_F=10\text{mA}$ $I_{OL}=13\text{mA}$ (Sinking)	-	0.4	0.6	V
"H Level Output \rightarrow L Level Output" Input Current	I_{FH}	$I_{OL}=13\text{mA}$ (Sinking) $V_{OL}=0.6\text{V}$	-	-	10	mA
High Level Supply Current	I_{CCH}	$V_{CC}=5.5\text{V}$, $I_F=0$	-	7	15	mA
Low Level Supply Current	I_{CCL}	$V_{CC}=5.5\text{V}$, $I_F=16\text{mA}$	-	12	18	mA
Input-Output Insulation Leakage Current	I_S	$V_S=3540\text{V}$, $t=5\text{s}$ $T_a=25^\circ\text{C}$ (Note 4)	-	-	100	μA
Isolation Resistance	R_S	R.H. $\leq 60\%$, $V_S=500\text{V DC}$ $T_a=25^\circ\text{C}$ (Note 4)	5×10^{10}	10^{12}	-	Ω
Stray Capacitance Between Input to Output	C_S	$V_S=0$, $f=1\text{MHz}$ $T_a=25^\circ\text{C}$ (Note 4)	-	0.8	-	pF

* All typical values are $V_{CC}=5\text{V}$, $T_a=25^\circ\text{C}$ SWITCHING CHARACTERISTICS ($V_{CC}=5\text{V}$, $T_a=25^\circ\text{C}$)

CHARACTERISTIC	SYMBOL	TEST CIRCUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Propagation Delay Time ($H \rightarrow L$)	t_{pHL}	1	$I_F=0 \rightarrow 16\text{mA}$ $C_L=15\text{pF}$, $R_L=350\Omega$	-	60	120	ns
Propagation Delay Time ($L \rightarrow H$)	t_{plH}	1	$I_F=16 \rightarrow 0\text{mA}$ $C_L=15\text{pF}$, $R_L=350\Omega$	-	60	120	ns
Output Rise-Fall Time (10-90%)	$t_{r,tf}$	2	$R_L=350\Omega$, $C_L=15\text{pF}$ $I_F=0 \rightarrow 16\text{mA}$	-	30	-	ns
Common Mode Transient Immunity at High Output Level	C_{MH}	2	$I_F=0\text{mA}$, $V_{CM}=200\text{Vp-p}$ $V_O(\text{MIN})=2\text{V}$, $R_L=350\Omega$	-	200	-	$\text{V}/\mu\text{s}$
Common Mode Transient Immunity at Low Output Level	C_{ML}	2	$I_F=16\text{mA}$, $V_{CM}=200\text{Vp-p}$ $V_O(\text{MAX})=0.8\text{V}$, $R_L=350\Omega$	-	-500	-	$\text{V}/\mu\text{s}$

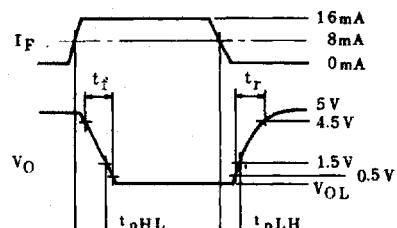
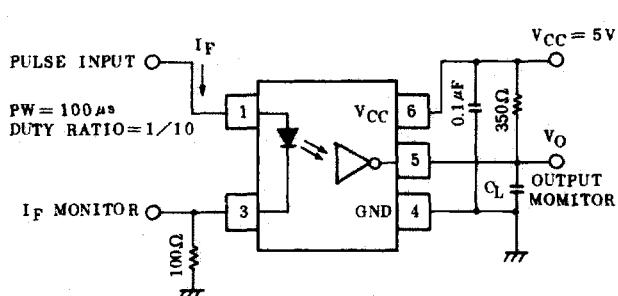
TLP113

Note 4 : Device considered a two-terminal device : Pins 1 and 3 shorted together and Pin 4,5 and 6 shorted together.

Note 5 : The V_{CC} supply voltage to each TLP113 isolator must be bypassed by $0.1\mu F$ capacitor. This can be either a ceramic or solid tantalum capacitor with good high frequency characteristic and should be connected as close as possible to package V_{CC} and GND pins of each device.

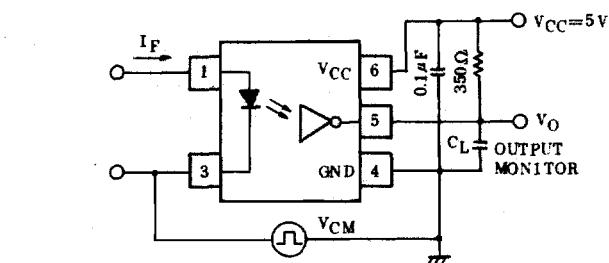
Note 6 : Maximum electrostatic discharge voltage for any pins : 180V ($C=200pF$, $R=0$)

TEST CIRCUIT 1 : Switching Time Test Circuit



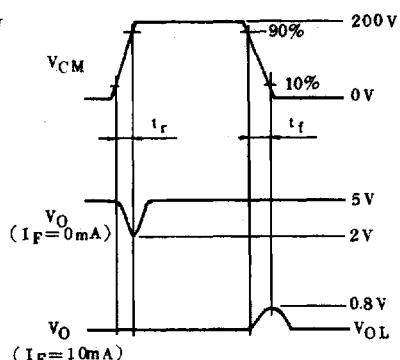
C_L is approximately $15pF$ which includes probe and stray wiring capacitance.

TEST CIRCUIT 2 : Common Mode Transient Immunity Test Circuit



PULSE GEN
 $Z_0 = 50\Omega$

$$CM_H = \frac{160 (V)}{t_r (\mu s)}, \quad CM_L = \frac{160 (V)}{t_f (\mu s)}$$



C_L is approximately $15pF$ which includes probe and stray wiring capacitance.